Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/709,815	BONALLE ET AL.	
Examiner	Art Unit	
Ahshik Kim	2876	

SEARCHED					
Class	Subclass	Date	Examiner		
235	379	2/10/2006	AK		
	380				
	381				
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Reviewd parent case 09764,688	2/10/2006	AK		
				